

74ALVC573

Octal D-type transparent latch; 3-state

Rev. 03 — 26 October 2007

Product data sheet

1. General description

The 74ALVC573 is an octal D-type transparent latch featuring separate D-type inputs for each latch and 3-state true outputs for bus-oriented applications. A latch enable (LE) input and an outputs enable ($\overline{OE}$) input are common to all latches.

When pin LE is HIGH, data at the D-inputs (pins D0 to D7) enters the latches. In this condition, the latches are transparent, that is, a latch output will change each time its corresponding D-input changes. When pin LE is LOW, the latches store the information that was present at the D-inputs one set-up time preceding the HIGH-to-LOW transition of pin LE.

When pin $\overline{OE}$ is LOW, the contents of the eight latches are available at the Q-outputs (pins Q0 to Q7). When pin $\overline{OE}$ is HIGH, the outputs go to the high-impedance OFF-state. Operation of input pin $\overline{OE}$ does not affect the state of the latches.

The 74ALVC573 is functionally identical to the 74ALVC373, but has a different pin arrangement.

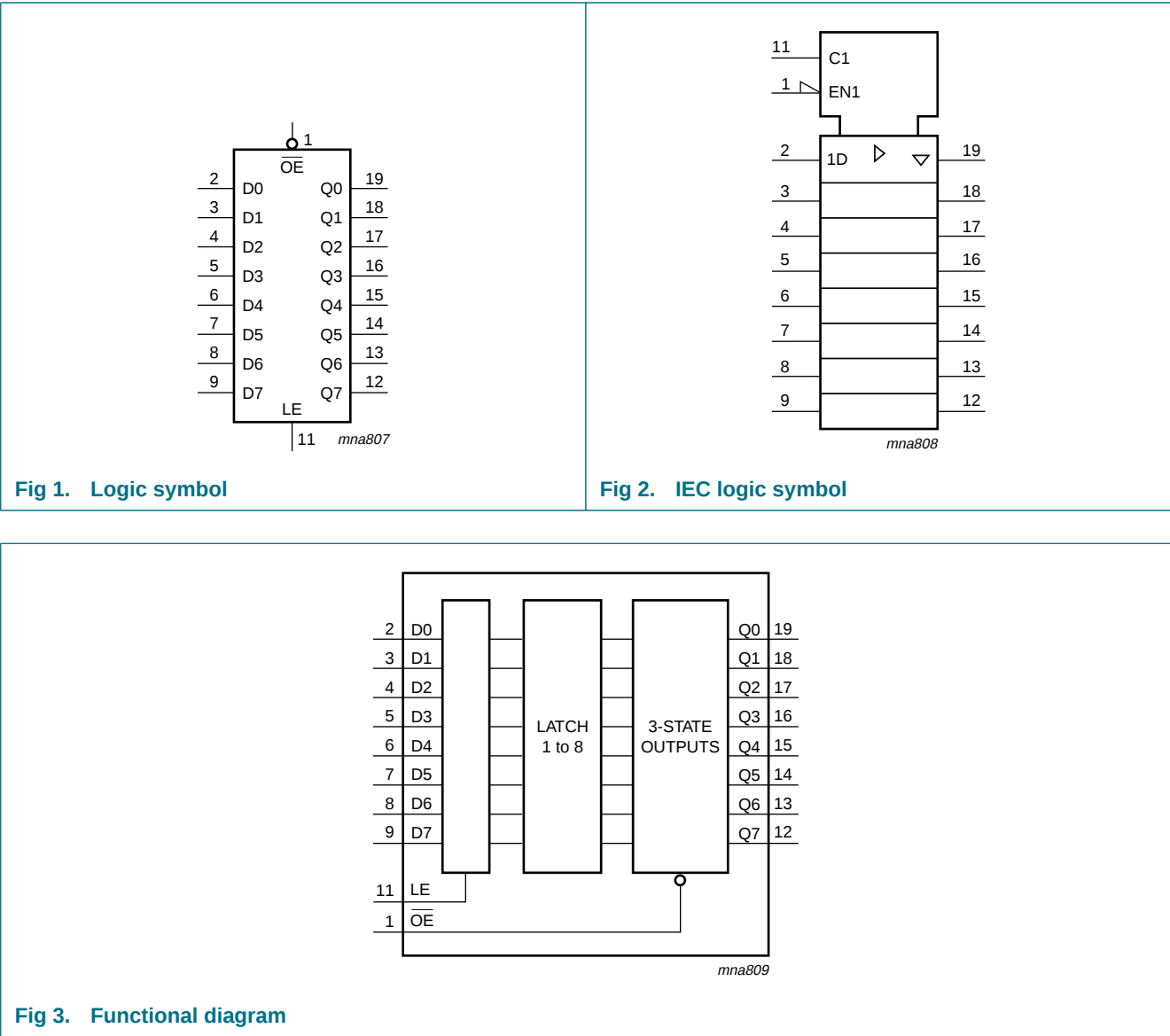
2. Features

- Wide supply voltage range from 1.65 V to 3.6 V
- 3.6 V tolerant inputs/outputs
- CMOS low power consumption
- Direct interface with TTL levels (2.7 V to 3.6 V)
- Power-down mode
- Latch-up performance exceeds 250 mA
- Complies with JEDEC standards:
 - ◆ JESD8-7 (1.65 V to 1.95 V)
 - ◆ JESD8-5 (2.3 V to 2.7 V)
 - ◆ JESD8B/JESD36 (2.7 V to 3.6 V)
- ESD protection:
 - ◆ HBM JESD22-A114E exceeds 2000 V
 - ◆ MM JESD22-A 115-A exceeds 200 V

3. Ordering information

Type number	Package			
	Temperature range	Name	Description	Version
74ALVC573D	−40 °C to +85 °C	SO20	plastic small outline package; 20 leads; body width 7.5 mm	SOT163-1
74ALVC573PW	−40 °C to +85 °C	TSSOP20	plastic thin shrink small outline package; 20 leads; body width 4.4 mm	SOT360-1
74ALVC573BQ	−40 °C to +85 °C	DHVQFN20	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 × 4.5 × 0.85 mm	SOT764-1

4. Functional diagram



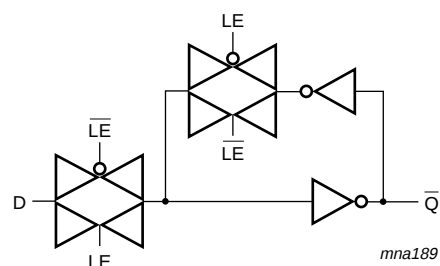


Fig 4. Logic diagram (one latch)

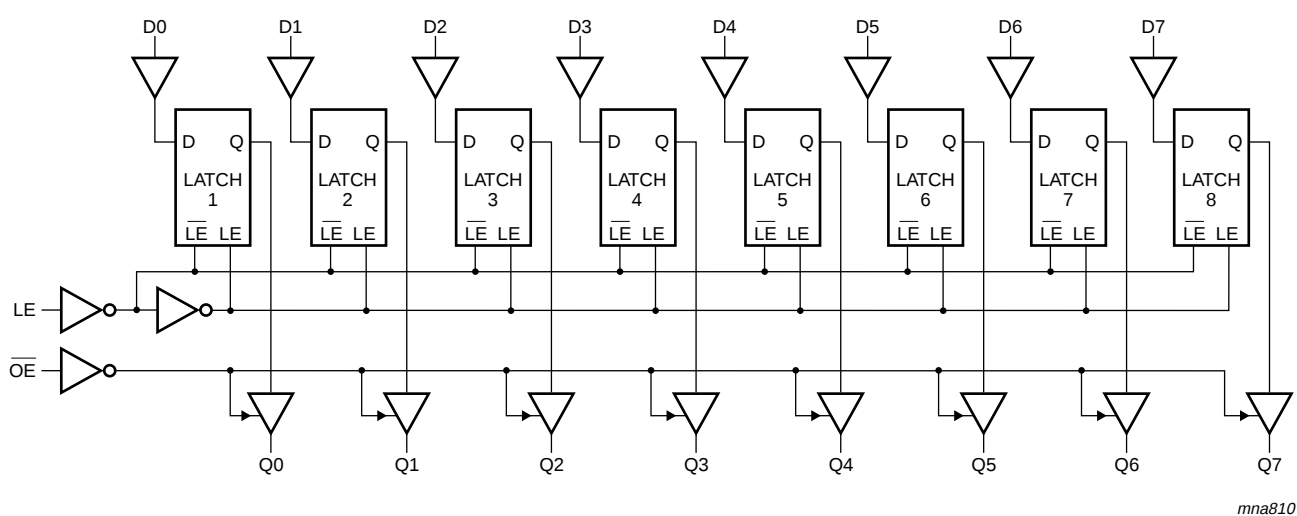
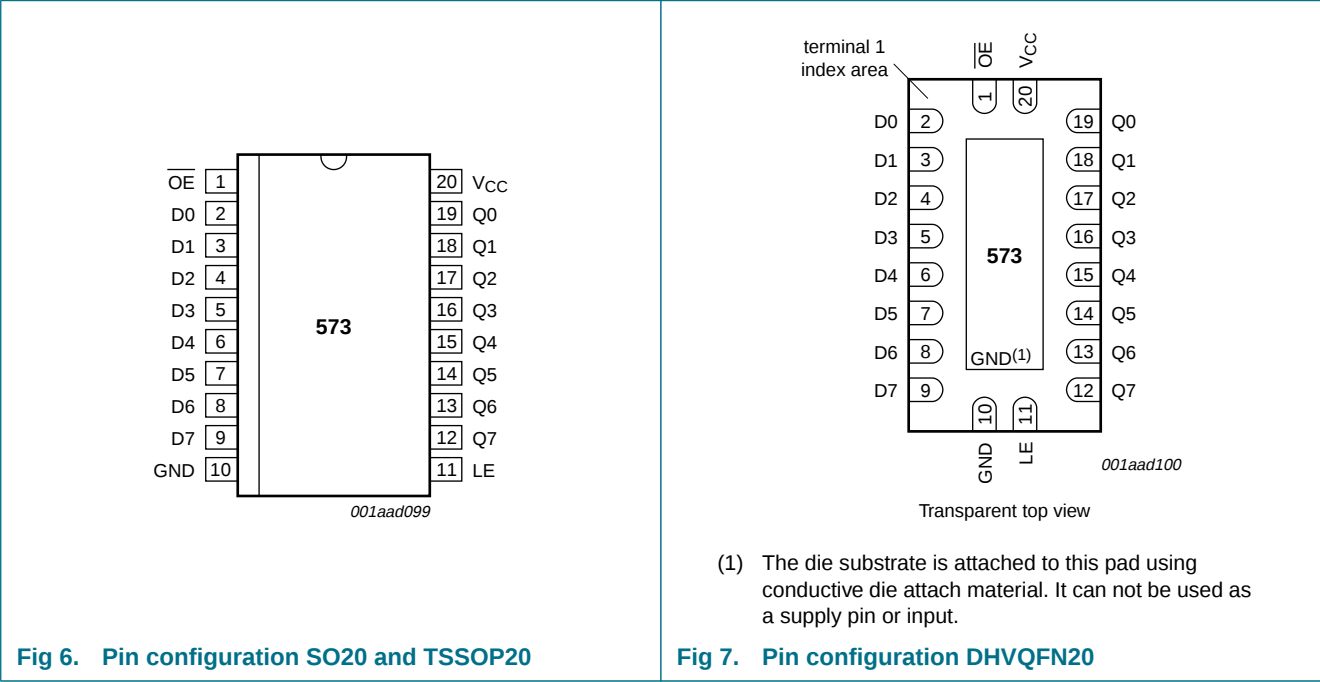


Fig 5. Logic diagram

5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
D[0:7]	2, 3, 4, 5, 6, 7, 8, 9	data input
LE	11	latch enable input (active HIGH)
OE	1	output enable input (active LOW)
Q[0:7]	19, 18, 17, 16, 15, 14, 13, 12	3-state latch output
V _{CC}	20	supply voltage
GND	10	ground (0 V)

6. Functional description

Table 3. Functional table^[1]

Operating modes	Input			Internal latch	Output Qn
	$\overline{OE}$	LE	Dn		
Enable and read register (transparent mode)	L	H	L	L	L
	L	H	H	H	H
Latch and read register	L	L	l	L	L
	L	L	h	H	H
Latch register and disable outputs	H	L	l	L	Z
	H	L	h	H	Z

- [1] H = HIGH voltage level
 h = HIGH voltage level one set-up time prior to the HIGH-to-LOW LE transition
 L = LOW voltage level
 l = LOW voltage level one set-up time prior to the HIGH-to-LOW LE transition
 Z = High-impedance OFF-state

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+4.6	V
I_{IK}	input clamping current	$V_I < 0$ V	-50	-	mA
V_I	input voltage		-0.5	+4.6	V
I_{OK}	output clamping current	$V_O > V_{CC}$ or $V_O < 0$ V	-	± 50	mA
V_O	output voltage	output HIGH or LOW state ^{[1] [2]}	-0.5	$V_{CC} + 0.5$	V
		output 3-state	-0.5	+4.6	V
		power-down mode, $V_{CC} = 0$ V ^[2]	-0.5	+4.6	V
I_O	output current	$V_O = 0$ V to V_{CC}	-	± 50	mA
I_{CC}	supply current		-	100	mA
I_{GND}	ground current		-100	-	mA
T_{stg}	storage temperature		-65	+150	°C
P_{tot}	total power dissipation	$T_{amb} = -40$ °C to +85 °C ^[3]	-	500	mW

- [1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 [2] When $V_{CC} = 0$ V (power-down mode), the output voltage can be 3.6 V in normal operation.
 [3] For SO20 packages: above 70 °C derate linearly with 8 mW/K.
 For TSSOP20 packages: above 60 °C derate linearly with 5.5 mW/K.
 For DHVQFN20 packages: above 60 °C derate linearly with 4.5 mW/K.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		1.65	3.6	V
V_I	input voltage		0	3.6	V
V_O	output voltage	output HIGH or LOW state	0	V_{CC}	V
		output 3-state	0	3.6	V
		power-down mode; $V_{CC} = 0$ V	0	3.6	V
T_{amb}	ambient temperature	in free air	-40	+85	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 1.65$ V to 2.7 V	-	20	ns/V
		$V_{CC} = 2.7$ V to 3.6 V	-	10	ns/V

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
V_{IH}	HIGH-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	$0.65 \times V_{CC}$	-	-	V
		$V_{CC} = 2.3$ V to 2.7 V	1.7	-	-	V
		$V_{CC} = 2.7$ V to 3.6 V	2.0	-	-	V
V_{IL}	LOW-level input voltage	$V_{CC} = 1.65$ V to 1.95 V	-	-	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3$ V to 2.7 V	-	-	0.7	V
		$V_{CC} = 2.7$ V to 3.6 V	-	-	0.8	V
V_{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}				
		$I_O = -100$ μ A; $V_{CC} = 1.65$ V to 3.6 V	$V_{CC} - 0.2$	-	-	V
		$I_O = -6$ mA; $V_{CC} = 1.65$ V	1.25	-	-	V
		$I_O = -12$ mA; $V_{CC} = 2.3$ V	1.8	-	-	V
		$I_O = -18$ mA; $V_{CC} = 2.3$ V	1.7	-	-	V
		$I_O = -12$ mA; $V_{CC} = 2.7$ V	2.2	-	-	V
		$I_O = -18$ mA; $V_{CC} = 3.0$ V	2.4	-	-	V
		$I_O = -24$ mA; $V_{CC} = 3.0$ V	2.2	-	-	V
V_{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}				
		$I_O = 100$ μ A; $V_{CC} = 1.65$ V to 3.6 V	-	-	0.2	V
		$I_O = 6$ mA; $V_{CC} = 1.65$ V	-	-	0.3	V
		$I_O = 12$ mA; $V_{CC} = 2.3$ V	-	-	0.4	V
		$I_O = 18$ mA; $V_{CC} = 2.3$ V	-	-	0.6	V
		$I_O = 12$ mA; $V_{CC} = 2.7$ V	-	-	0.4	V
		$I_O = 18$ mA; $V_{CC} = 3.0$ V	-	-	0.4	V
		$I_O = 24$ mA; $V_{CC} = 3.0$ V	-	-	0.55	V
I_I	input leakage current	$V_{CC} = 3.6$ V; $V_I = 3.6$ V or GND	-	± 0.1	± 5	μ A

Table 6. Static characteristics ...continued

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	–40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
I _{OZ}	OFF-state output current	V _I = V _{IH} or V _{IL} ; V _{CC} = 1.65 V to 3.6 V; V _O = 3.6 V or GND;	-	±0.1	±10	μA
I _{OFF}	power-off leakage supply	V _{CC} = 0 V; V _I or V _O = 0 V to 3.6 V	-	±0.1	±10	μA
I _{CC}	supply current	V _{CC} = 3.6 V; V _I = V _{CC} or GND; I _O = 0 A	-	0.2	10	μA
ΔI _{CC}	additional supply current	per input pin; V _{CC} = 3.0 V to 3.6 V; V _I = V _{CC} – 0.6 V; I _O = 0 A	-	5	750	μA
C _I	input capacitance		-	3.5	-	pF

[1] All typical values are measured at V_{CC} = 3.3 V (unless stated otherwise) and T_{amb} = 25 °C.

10. Dynamic characteristics

Table 7. Dynamic characteristicsVoltages are referenced to GND (ground = 0 V). For test circuit see [Figure 12](#).

Symbol	Parameter	Conditions	–40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
t _{pd}	propagation delay	Dn to Qn; see Figure 8 ^[2]				
		V _{CC} = 1.65 V to 1.95 V	1.0	2.5	5.4	ns
		V _{CC} = 2.3 V to 2.7 V	1.0	2.0	3.5	ns
		V _{CC} = 2.7 V	1.0	2.3	3.6	ns
		V _{CC} = 3.0 V to 3.6 V	1.0	2.2	3.3	ns
		LE to Qn; see Figure 9				
		V _{CC} = 1.65 V to 1.95 V	1.0	2.8	6.0	ns
		V _{CC} = 2.3 V to 2.7 V	1.0	2.1	3.8	ns
		V _{CC} = 2.7 V	1.0	2.4	3.7	ns
		V _{CC} = 3.0 V to 3.6 V	1.0	2.3	3.3	ns
t _{en}	enable time	OE to Qn; see Figure 10 ^[2]				
		V _{CC} = 1.65 V to 1.95 V	1.5	3.0	6.4	ns
		V _{CC} = 2.3 V to 2.7 V	1.0	2.4	4.5	ns
		V _{CC} = 2.7 V	1.5	3.0	4.6	ns
		V _{CC} = 3.0 V to 3.6 V	1.0	2.3	4.0	ns
t _{dis}	disable time	OE to Qn; see Figure 10 ^[2]				
		V _{CC} = 1.65 V to 1.95 V	1.5	3.4	7.0	ns
		V _{CC} = 2.3 V to 2.7 V	1.0	2.2	4.4	ns
		V _{CC} = 2.7 V	1.5	2.8	4.4	ns
		V _{CC} = 3.0 V to 3.6 V	1.0	2.7	4.4	ns

Table 7. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V). For test circuit see [Figure 12](#).

Symbol	Parameter	Conditions	–40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
t_W	pulse width	LE pulse width HIGH; see Figure 9				
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	3.8	-	-	ns
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	3.3	-	-	ns
		$V_{CC} = 2.7 \text{ V}$	3.3	-	-	ns
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	3.3	-	-	ns
t_{su}	set-up time	Dn to LE; see Figure 11				
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	0.8	-	-	ns
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.8	-	-	ns
		$V_{CC} = 2.7 \text{ V}$	0.8	-	-	ns
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	0.8	-	-	ns
t_h	hold time	Dn to LE; see Figure 11				
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	0.8	-	-	ns
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.8	-	-	ns
		$V_{CC} = 2.7 \text{ V}$	0.8	-	-	ns
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	0.7	-	-	ns
C_{PD}	power dissipation capacitance	per latch; $V_I = \text{GND to } V_{CC}$; $V_{CC} = 3.3 \text{ V}$ ^[3]				
		outputs HIGH or LOW state	-	37	-	pF
		outputs 3-state	-	7	-	pF

[1] Typical values are measured at $T_{amb} = 25 \text{ °C}$

[2] t_{pd} is the same as t_{PHL} and t_{PLH} .

t_{en} is the same as t_{PZH} and t_{PZL} .

t_{dis} is the same as t_{PHZ} and t_{PLZ} .

[3] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:

f_i = input frequency in MHz; f_o = output frequency in MHz

C_L = output load capacitance in pF

V_{CC} = supply voltage in Volts

N = number of inputs switching

$\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs

11. Waveforms

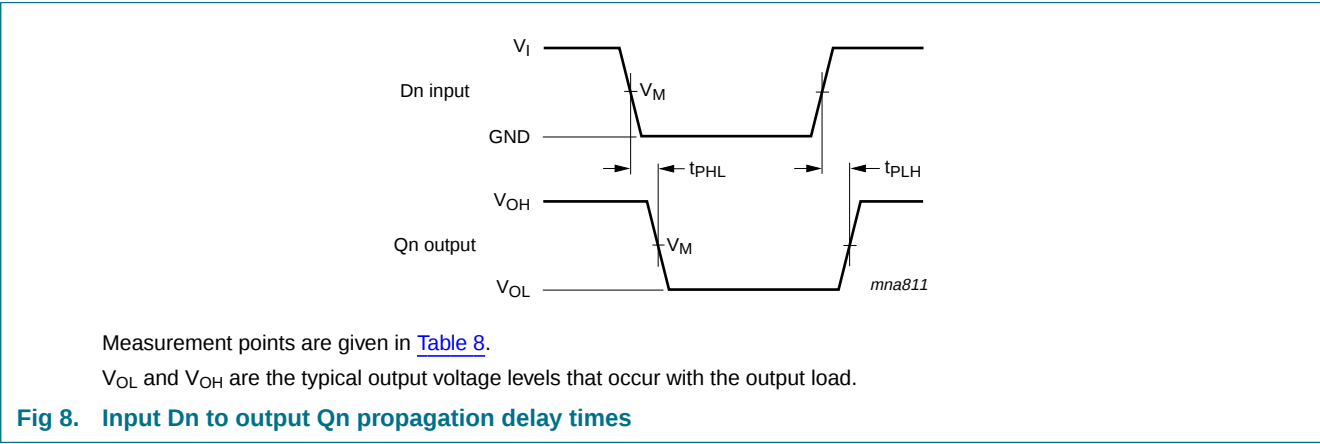
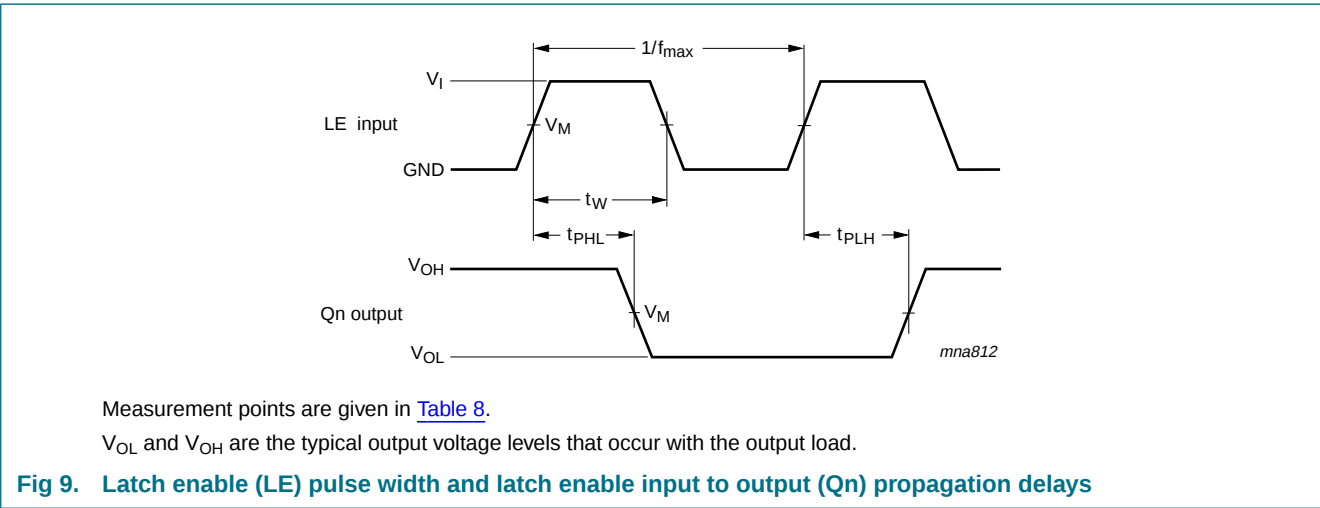


Table 8. Measurement points

Supply voltage V_{CC}	V_M	Output	
		V_X	V_Y
1.65 V to 1.95 V	$0.5V_{CC}$	$V_{OL} + 0.15\text{ V}$	$V_{OH} - 0.15\text{ V}$
2.3 V to 2.7 V	$0.5V_{CC}$	$V_{OL} + 0.15\text{ V}$	$V_{OH} - 0.15\text{ V}$
2.7 V	1.5 V	$V_{OL} + 0.3\text{ V}$	$V_{OH} - 0.3\text{ V}$
3.0 V to 3.6 V	1.5 V	$V_{OL} + 0.3\text{ V}$	$V_{OH} - 0.3\text{ V}$



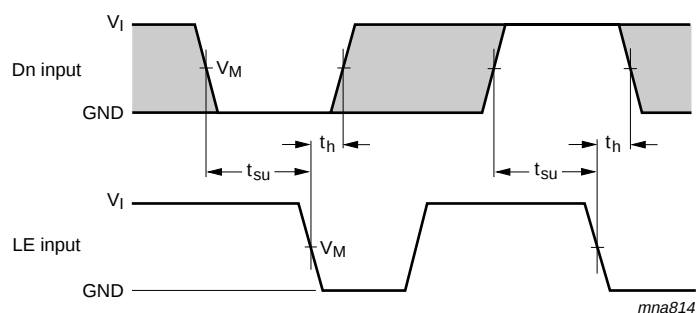
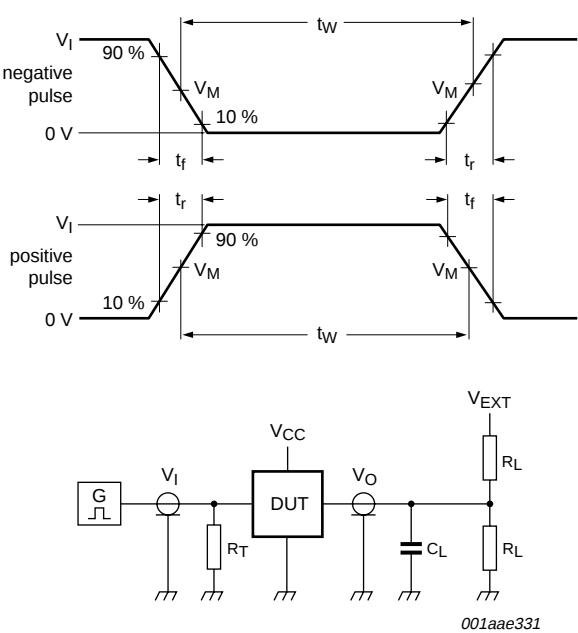


Fig 11. The data set-up and hold times for Dn input to LE input



Test data is given in [Table 9](#).
Definitions for test circuit:
 R_L = Load resistance.
 C_L = Load capacitance including jig and probe capacitance.
 R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.
 V_{EXT} = External voltage for measuring switching times.

Fig 12. Test circuitry for switching times

Table 9. Test data

Supply voltage	Input		Load		V_{EXT}		
	V_I	t_r, t_f	C_L	R_L	t_{PLH}, t_{PHL}	t_{PLZ}, t_{PZL}	t_{PHZ}, t_{PZH}
1.65 V to 1.95 V	V_{CC}	≤ 2.0 ns	30 pF	1 k Ω	open	$2V_{CC}$	GND
2.3 V to 2.7 V	V_{CC}	≤ 2.0 ns	30 pF	500 Ω	open	$2V_{CC}$	GND
2.7 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	6 V	GND
3.0 V to 3.6 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	6 V	GND

12. Package outline

SO20: plastic small outline package; 20 leads; body width 7.5 mm SOT163-1

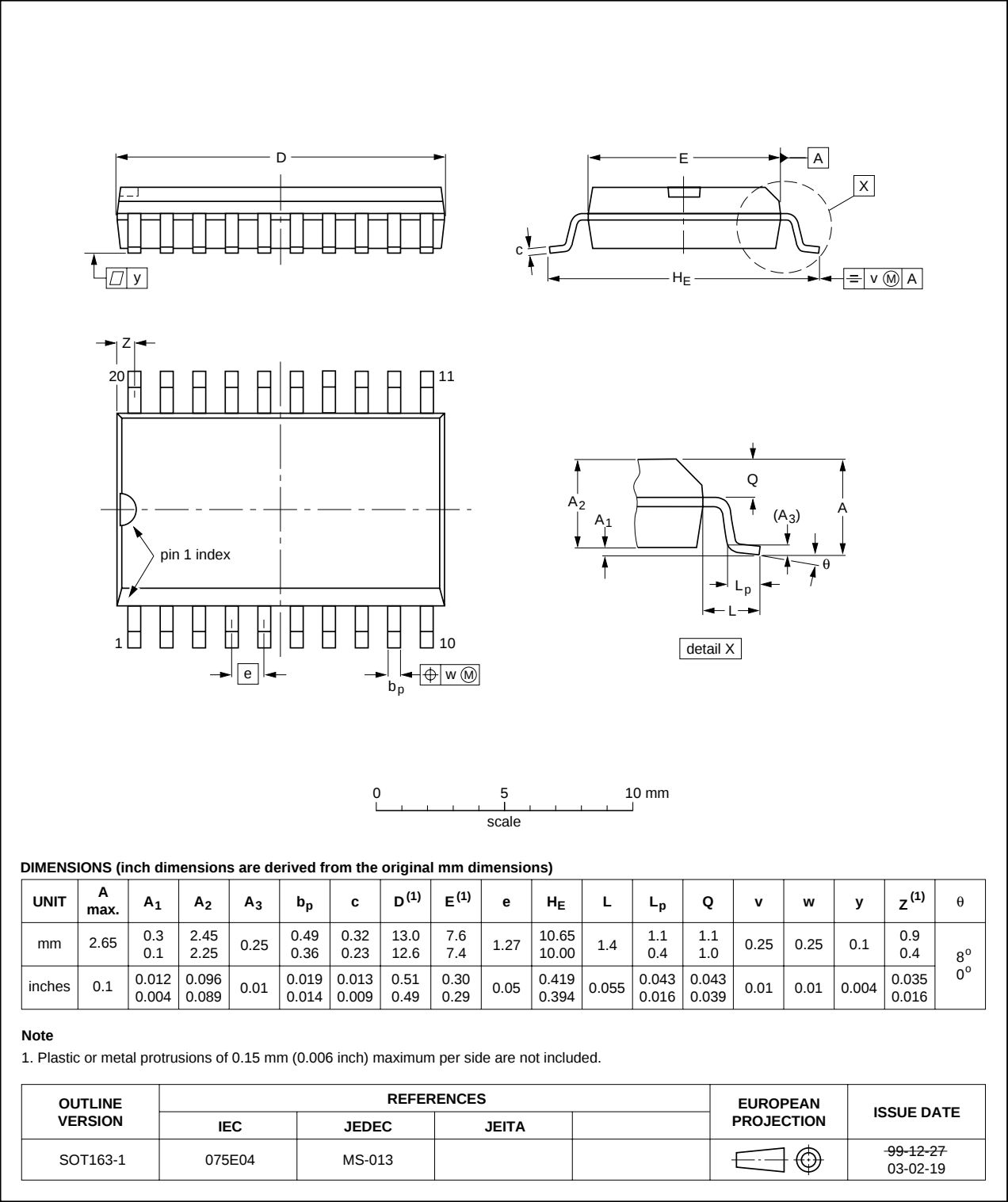
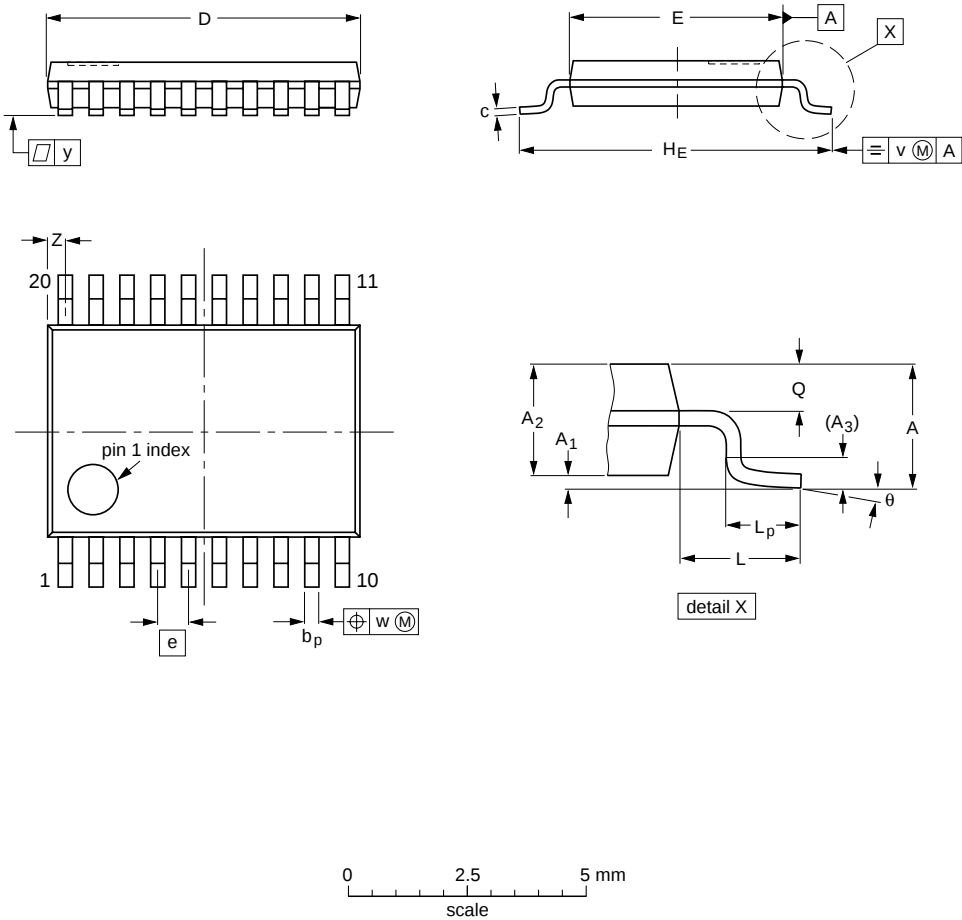


Fig 13. Package outline SOT163-1 (SO20)

TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm

SOT360-1



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	b _p	c	D ⁽¹⁾	E ⁽²⁾	e	H _E	L	L _p	Q	v	w	y	z ⁽¹⁾	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	6.6 6.4	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8° 0°

- Notes**
1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT360-1		MO-153				-99-12-27 03-02-19

Fig 14. Package outline SOT360-1 (TSSOP20)

DHVQFN20: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 x 4.5 x 0.85 mm

SOT764-1

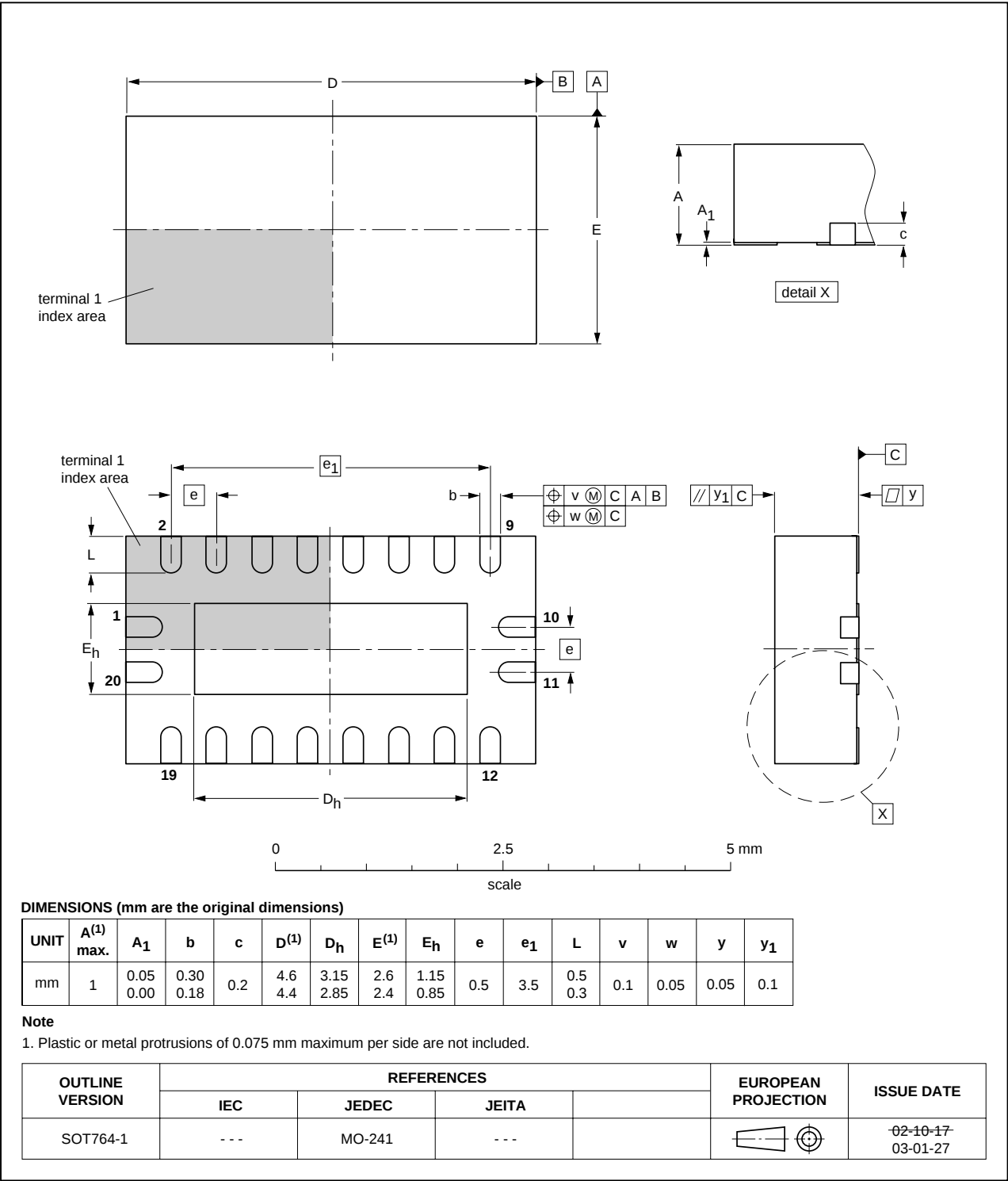


Fig 15. Package outline SOT764-1 (DHVQFN20)

13. Abbreviations

Table 10. Abbreviations

Acronym	Description
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

14. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVC573_3	20071026	Product data sheet	-	74ALVC573_2
Modifications:	• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Legal texts have been adapted to the new company name where appropriate. • Section 3: DHVQFN20 package added. • Section 8: derating values added for DHVQFN20 package. • Section 12: outline drawing added for DHVQFN20 package.			
74ALVC573_2	20030625	Product specification	-	74ALVC573_1
74ALVC573_1	20020301	Product specification	-	-

15. Legal information

15.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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